

Application No.	Applicant(s)	
09/873,815	LAVORGNA ET AL.	
Examiner	Art Unit	
Tan Dean D. Nouven	3629	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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